# Structural, Morphological, Compositional, Electrical, and Optical Characterizations of CuZnS Thin Films Prepared using Chemical Bath Deposition Method

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#### Abstract

The universality, affordability and abundance of solar energy combined with its free and high energy output make it an exceptional renewable energy source. Solar cells play a vital role in converting sunlight into electrical energy. CuZnS has gained significant attention as a potential absorber material for solar cells. In the present work, we report the preliminary results of the preparation of CuZnS thin films using a relatively low-cost Chemical Bath Deposition technique, from a precursor solution containing 0.1M concentrations of copper chloride, zinc chloride, and thiourea. Triethanolamine (TEA) is used as the complexing agent, and ammonia is used to control the pH of the solution. The samples were prepared by keeping the pH at 11.6, maintaining the temperature at 80°C, and a deposition time of 1 hour. Structural, morphological, compositional, electrical, and optical analyses of the prepared samples were done. From the SEM analysis grain size calculated is 177 nm. The observed bandgap value was 2.61 eV at a Cu/(Cu+Zn) ratio of 83%. The prepared sample is a p-type semiconductor with a conductivity  $1.646X10^{-3}\Omega^{-1}$ cm<sup>-1</sup>. XRD [Bruker Kappa Apex II], SEM-EDAX [Jeol 6390LA/OXFORD XMX N], Hall effect measurement system [Ecopia HMS 3000s], and UV-Vis Spectrophotometry [JASCO V-670 UV-Vis NIR Spectrophotometer] were used for the characterization of the samples.

**Keywords**: CuZnS, Chemical bath deposition, Preparation of thin film, Characterization of thin film. Received 28 January 2025; First Review 22 March 2025; Accepted 24 April 2025.

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# Introduction

CuZnS is a semiconductor with highly desirable photovoltaic properties, including a high absorption coefficient and a direct bandgap. The direct bandgap energy varies from 1.8 to 3.5 eV as the Cu/(Cu+Zn) ratio increases from 0 to 67%. CuZnS film prepared using spray pyrolysis with Cu/(Cu+Zn) ratio of 50% exhibited a bandgap of 2 eV [1]). Reported bandgap for the CuZnS films prepared using the SILAR method is 2.4 to 2.6 eV for copper-rich CuZnS samples [2]. In our present study the observed bandgap value was 2.61 eV at a Cu/(Cu+Zn) ratio of 83%. These thin films are used as an absorber or window layer, and their electrical and optical characteristics can be adjusted by changing the atomic ratios of copper and zinc [3-5]. Furthermore, CuZnS cells employ affordable, nontoxic, and plentiful (rare-earth-free) metals [2]. It is a favorable material for numerous applications in photovoltaic cells and photoconductor devices [6-8]. Ternary materials are appropriate for use in window-layer solar cells and optoelectronic devices [9]. The various techniques used to develop thin films include thermal evaporation [10], chemical spray pyrolysis [1], successive ionic layer adsorption and reaction [2], electrochemical deposition [11], photochemical deposition [12], pulsed laser deposition [13] and chemical bath deposition [14]. The chemical bath deposition method has drawn much attention due to its low cost, non-toxicity, ease of use, and compatibility for large-area deposition and film homogeneity [15,16]. In this study, we used the chemical bath deposition method to prepare CuZnS thin films and electrical, optical, morphological, structural, and compositional characterizations of these films were done.

## **Experimental Details**

#### 1. Materials

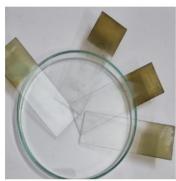
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CuZnS thin film was prepared using a low-cost chemical bath deposition technique. The precursor solution contains copper chloride, zinc chloride, triethanolamine (TEA), ammonia, and thiourea. TEA acts as a complexing agent, and ammonia regulates the pH of the solution. Samples were prepared to optimize the molarity of the reactants, amount of TEA, pH of the solution, deposition time, and temperature. Magnetic stirrer was used to mix the solution during the deposition process. Thoroughly cleaned and dried glass substrates were placed in the precursor solution. The glass plates were kept in the solution for one hour at a temperature of 80 °C. The best sample was obtained from a solution containing 5 ml of 0.1M copper chloride, 5 ml of 0.1M zinc chloride, 10 ml of 0.1M thiourea, 4 ml of TEA, and 3 ml of ammonia. This film was analysed using different characterization techniques.

#### 2. Method

To prepare the thin film, 2 ml of Triethanolamine (TEA) was mixed with 5ml of 0.1M copper chloride solution to form a complex. Then, 2 ml of TEA and 3ml of ammonia were mixed into 5 ml of 0.1 M zinc chloride solution to make another complex. The individually made complexes were combined and thoroughly stirred for 5 minutes until homogeneous. 10 ml of 0.1 M thiourea and 5 ml of distilled water were added dropwise from the burette to the solution while stirring. Then the solution was heated to 80°C using a water bath, and well-cleaned glass substrates were dipped in it for one hour, maintaining a constant temperature. The solution gradually changes its colour from blue to brown, and glass substrates are uniformly coated with CuZnS. These films were washed, dried, and used for various analyses. Figure 1 shows the experimental setup and the CuZnS samples prepared using CBD.





**Figure 1**: Experimental setup and the CuZnS samples prepared using CBD.

## **Results and Discussion**

## X-ray Diffraction Spectroscopy (XRD)

XRD can provide information on the material structure, phase composition, and crystal characteristics of prepared thin films [17]. Additionally, we can identify whether the

thin film is crystalline or amorphous. For XRD analysis is, Bruker Kappa Apex II with CuK $\alpha$  wavelength 1.5406 Å was used. The XRD spectrum spans the 2 $\theta$  range from 10° to 90°. Figure 2 depicts the XRD pattern of the CuZnS thin film, with the broadening of peaks reflecting the formation of nanoparticles.

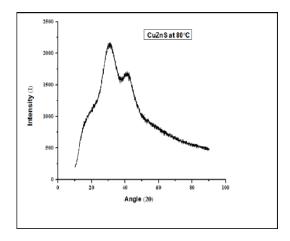


Figure 2: XRD pattern of CuZnS thin films prepared by CBD method

The structural study of CuZnS thin film samples obtained by XRD shows two peaks, one at  $30.881^{\circ}$  and the other at  $41.066^{\circ}$ .

**Table 1:** Comparison of observed values with ICSD standard reference code.

Chemical	Stand	Intensi	Obser	Observ	h	D[Å	
formula	ard	ty (in	ved	ed	k	i	
	2θ	percent	2θ	Intensi		-	
	Value	age)	Value	ty (in	1		
	s		S	percent			
				age)			
ICSD Reference code: 98-062-8980							
Cu(0.12)Zn(3.	30.01	100	30.88	100	0	2.97	
88)S2(4)	8		1		0	45	
					2		
	42.96	50.3	41.06	<b>79</b>	0		
	7		6			2.10	
					2	33	
					2		
ICSD Reference code: 98-062-8979							
Cu(3.2)Zn(0.8	30.68	100	30.88	100	0	2.91	
)	3		1			15	
S2(4)					0		
					2		
	12.04	40.7		79	_	2.05	
	43.94 5	48.7	41.06	19	0	2.05 87	
	3		6		2	0/	
			U		4		
					2		
					4		

These peak values are compared with the standard ICSD reference values (ICSD Ref codes 98-062-8979 and 98-062-8980), which are listed in Table 1. The two peak values

correlate to the ICSD values for planes (002) and (022), indicating a cubic structure based on these ICSD values. The hundred percentage peak matched well with ICSD Ref code 98-062-8979, while the second peak has a 1° discrepancy in 20 value compared to ICSD Ref codes of Cu((0.12)Zn(3.88)S2(4)). The change in results could be attributed to the existence of distinct phases of CuZnS in the sample or to variations in the Cu to Zn ratio. The crystallite size of the material can be calculated using the Debye–Scherrer formula from X-ray diffraction (XRD) data.

$$D = \frac{K\lambda}{\beta \ Cos\theta}$$

Where:

D = average crystallite size

 $K = Scherrer constant \sim 0.94$  (depends on shape factor)

 $\lambda = X$ -ray wavelength in nm or Å, 1.5406 Å for Cu K $\alpha$  lines

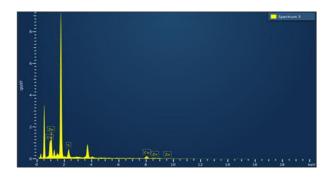
 $\beta$  = Full width at half maximum of the peak in radians

 $\theta$  = Bragg angle

The crystallite size calculated using Debye-Scherrer formula is 1.35nm.

## **Energy Dispersive X-ray Spectroscopy (EDAX)**

Energy Dispersive X-ray spectroscopy analysis was used to determine the elemental composition of the CuZnS sample [18]. The EDAX spectrum of the sample is displayed in Figure 3.



**Figure 3.** EDAX spectrum of CuZnS thin film prepared by CBD method.

Table 2: Elemental composition of CuZnS.

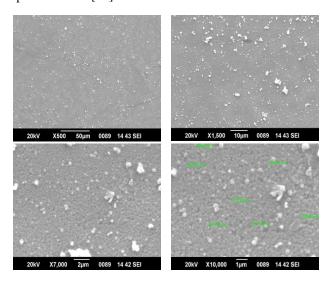
Element	Line Type	Wt %	Atomic%	
Cu	K series	55.43	41.72	
Zn	K series	10.77	7.88	
S	K series	33.79	50.40	
Total	K series	100	100	

The atomic and weight percentages of the given sample are shown in Table 2. The CuZnS sample has an atomic percentage ratio of 41.72:7.88:50.40, and weight

percentages of 55.43:10.77:33.79. Elemental analysis reveals that the prepared samples are enriched in copper with a low percentage of zinc. Zn deficiency has been reported in CuZnS thin films generated via the Silar technique [2]. Attempts are being made to improve the Zn content in the samples.

#### Scanning Electron Microscopy (SEM)

SEM examined the surface topography, microstructure and grain size of the CuZnS thin film samples [18,19]. This study exposes characteristics including conductivity and optical behaviour. There are no obvious cracks on the surface of the thin film. The particles are spherical in shape, nanostructured, uniform, and densely packed, making them suitable for photovoltaic applications. The thickness of the thin film was measured using a Dektak stylus profilometer and found to be 131 nm. Figure 4 (a), (b), (c), and (d) displays SEM images of CuZnS at varying resolutions (50 μm, 10 μm, 2 μm, 1 μm). The average particle size calculated from SEM analysis is 177nm. This is different from the value obtained from XRD (less than 5nm). It may be due to the grains themselves must be formed by the merging of closely packed nanocrystallites. This has been reported earlier [18].



**Figure 4:** (a), (b), (c), (d) SEM images of CuZnS thin film prepared by CBD method.

#### **UV Visible spectroscopy**

The analytical method (UV-Vis) is used to determine the optical properties, electrical structure, and material composition of the sample. JASCO V-670 UV-Vis NIR Spectrophotometer was used for optical analysis. The optical absorption spectra of CuZnS thin films were studied within 350 and 900 nm. Figure 5 shows the absorption spectra of CuZns. The direct bandgap of CuZnS was determined using a Tauc's plot ( $(\alpha h \upsilon)$ 2 vs. hv plot) [20]. Figure 6 shows the Tauc's plot of CuZnS, with a bandgap value of 2.61eV. This value falls within the standard range 1.8 - 3.5 eV reported

in spray pyrolysis [1]) and 2.4 to 2.6 eV reported in SILAR method is for copper-rich CuZnS samples [2].

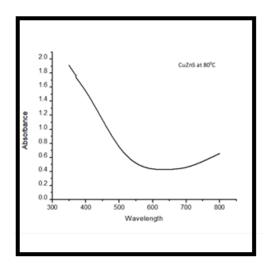


Figure 5: Absorption spectra of CuZnS thin film.

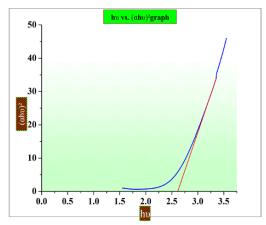


Figure 6: Tauc's plot (Direct bandgap of CuZnS thin film)

## Hall Effect measurement

The Hall Effect measurement technique is extremely accurate for electrical analysis. The Hall coefficient value can detect whether the material is p-type or n-type. Thin film samples are analyzed to determine the sample's bulk concentration, mobility, sheet resistance, resistivity, conductivity, and average Hall coefficient. Optimizing semiconductor electrical properties can improve their applications in solar cells as well as sensors. Based on the Hall coefficient measurement of the CuZnS samples, the average Hall coefficient value obtained is  $4.701 \times 10^4 \text{cm}^3/\text{C}$ . This clearly indicates that the prepared samples are of p-type conductivity.

The conductivity of the sample is  $1.646 \times 10^{-3} \ \Omega^{-1} cm^{-1}$ . The conductivity value reported earlier for thermal evaporated film is 63.3  $\Omega^{-1} cm^{-1}$  [10] and for MOCVD (Metal oxide chemical vapour deposition method) is  $5.48 \times 10^{-1}$  to  $8.0 \times 10^{-1} \ \Omega^{-1} cm^{-1}$  [15]. Table 3 shows the Hall parameters of CuZnS thin films.

Table 3. Hall parameters of CuZnS thin film

Hall Parameters				
Bulk concentration in cm <sup>3</sup>	$1.328 \times 10^{14}$			
Mobility in cm <sup>2</sup> /vs	$7.738x10^{1}$			
Sheet resistance in Ω/sq	$4.637 \times 10^7$			
Resistivity in Ωcm	$6.075 \times 10^2$			
Conductivity in Ω-1cm-1	1.646x10 <sup>-3</sup>			
Average Hall coefficient in cm <sup>3</sup> /C	4.701x10 <sup>4</sup>			

## Conclusion

The CuZnS samples are relatively homogeneous. The XRD study confirms that the hundred percentage peak corresponds to ICSD Ref code 98-062-8980. However, the second peak differs by 1° in 20 value from the same ICSD Ref code. The EDAX analysis reveals that the prepared samples are enriched in copper with a low percentage of zinc. SEM analysis revealed that the particles exhibited a spherical shape and the average particle size is 177nm. The samples are more or less uniform. Based on the optical characterization, the prepared sample has a bandgap energy of 2.61 eV. The average Hall coefficient value of  $4.701 \times 10^4 \text{cm}^3/\text{C}$  indicates that the prepared sample is a ptype semiconductor. The samples resistivity is  $6.075 \times 10^2$  and conductivity is  $1.646 \times 10^{-3} \Omega^{-1} \text{cm}^{-1}$ , these values fall within the benchmark value for semiconductors.

## **Future plans**

As the samples exhibit Zn deficiency, further research is needed to increase the Zn content. Attempts are being made to improve the Zn content and to make the film more stoichiometric.

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